

# TSTE25 Power Electronics

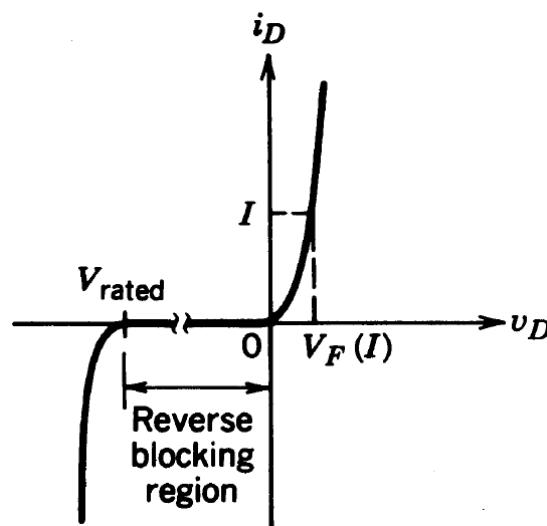
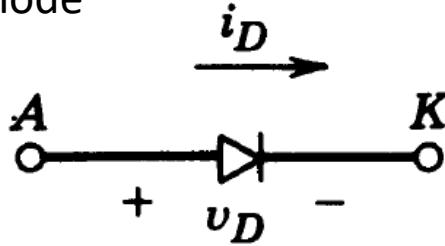
Lecture 4  
Tomas Jonsson  
ISY/EKS

# Outline

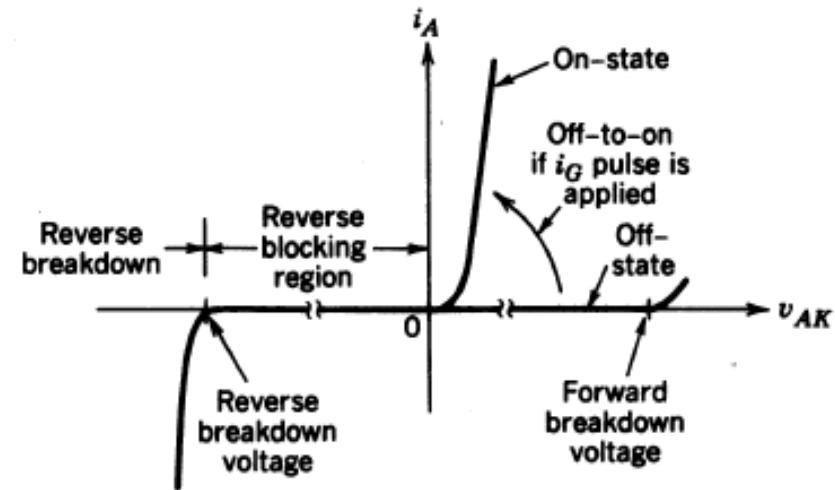
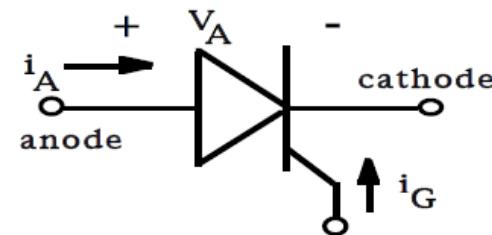
- Semiconductor switches
- Loss calculation
- Switching equivalents
- Thermal aspects

# Semiconductors without turn-off capability

Diode

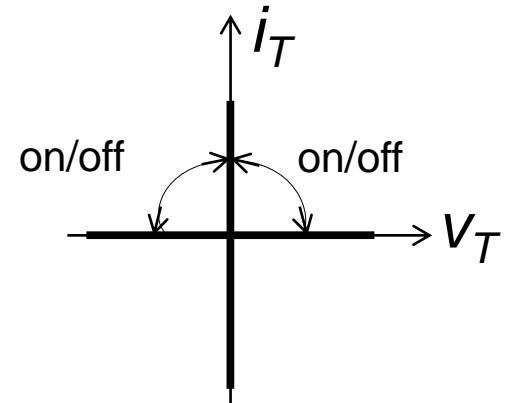
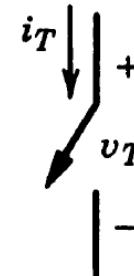


Thyristor circuit symbol.



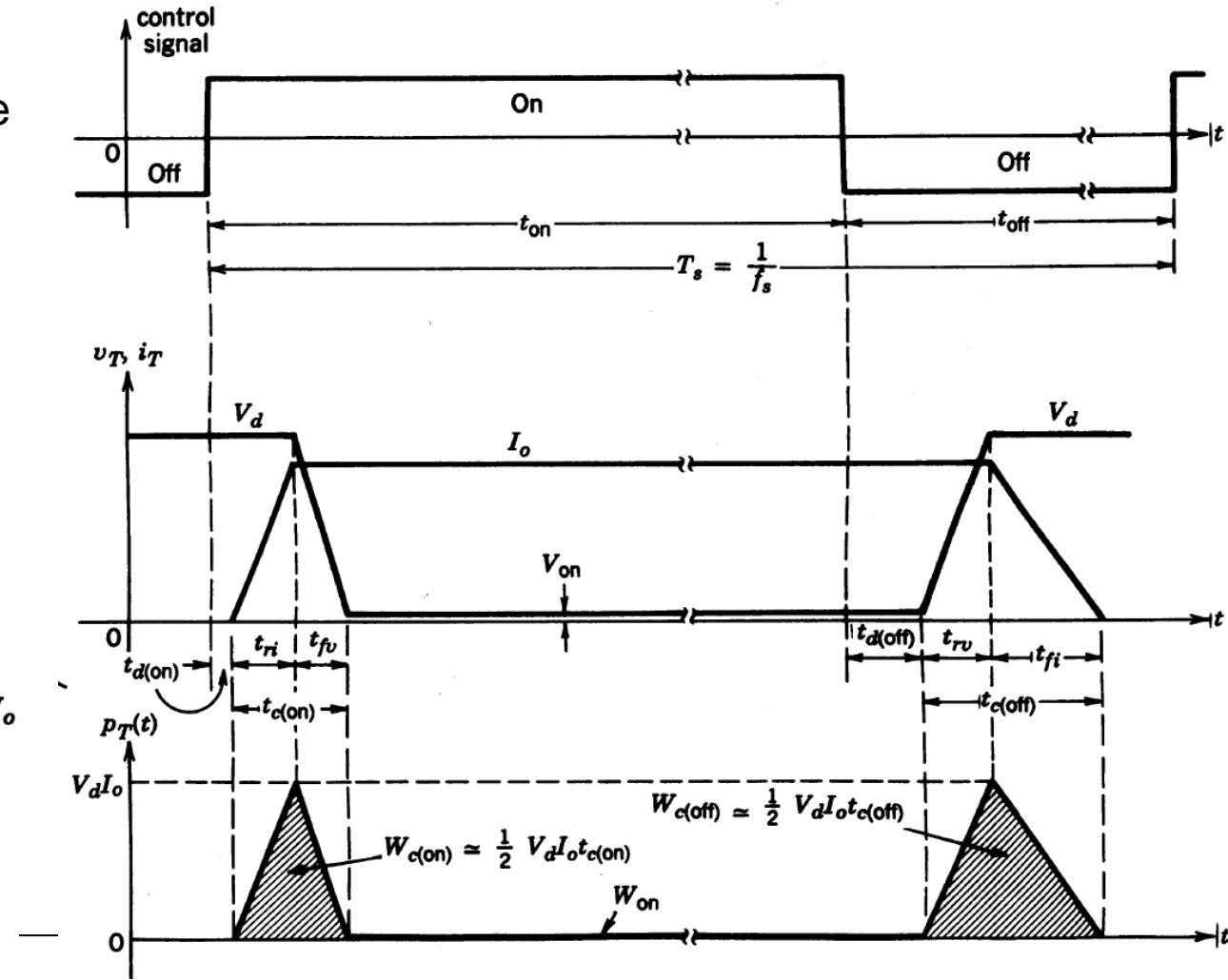
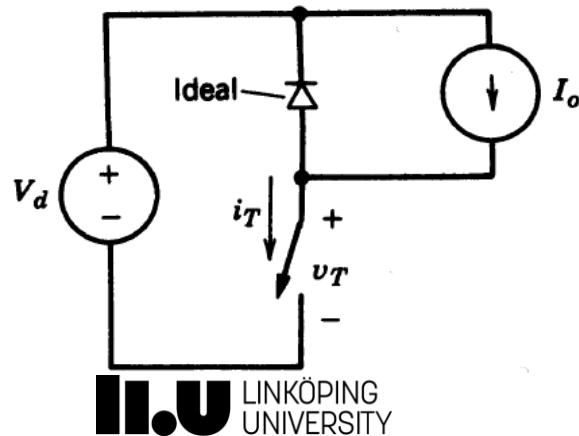
# Ideal switch

- Accept voltages of both polarities
  - Both negative and positive
- Controlled turn-on and turn-off
- Conduct current in both directions
- No breakdown voltage
  - Perfect isolation in off state
- Zero on-resistance
  - No voltage drop over the switch
- No switch delay
- Zero energy switching
  - No power dissipated during operation



# Non-ideal switch example

- Linear model
  - Rise and fall time on both V and I
  - Voltage drop  $V_{on}$
  - $I_0$  models an inductor
- Power loss!



# DC/DC converter losses

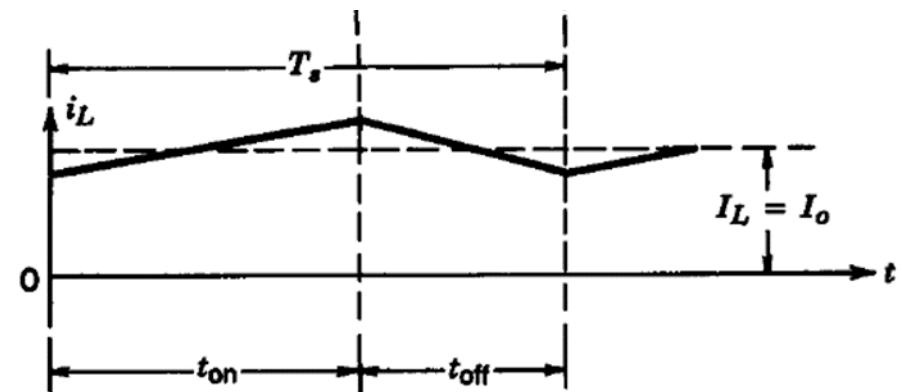
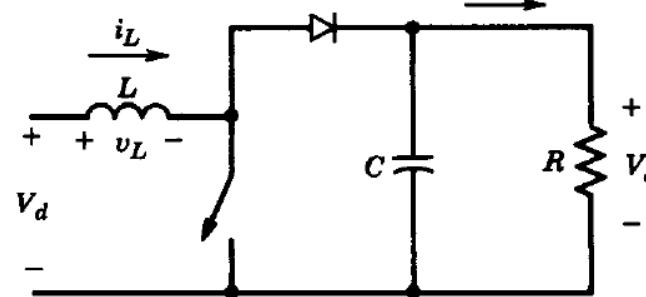
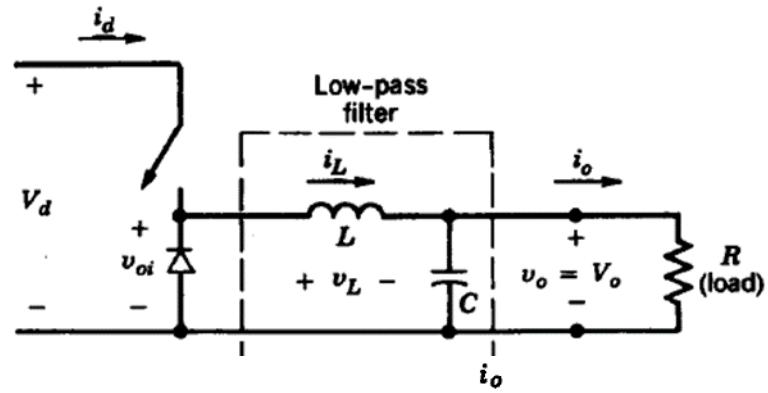
## Conduction losses

- $P_{on} = r_{ds(on)} I_{sw,rms}^2 = D \cdot r_{ds(on)} I_{L,av}^2$

## Switching losses (average)

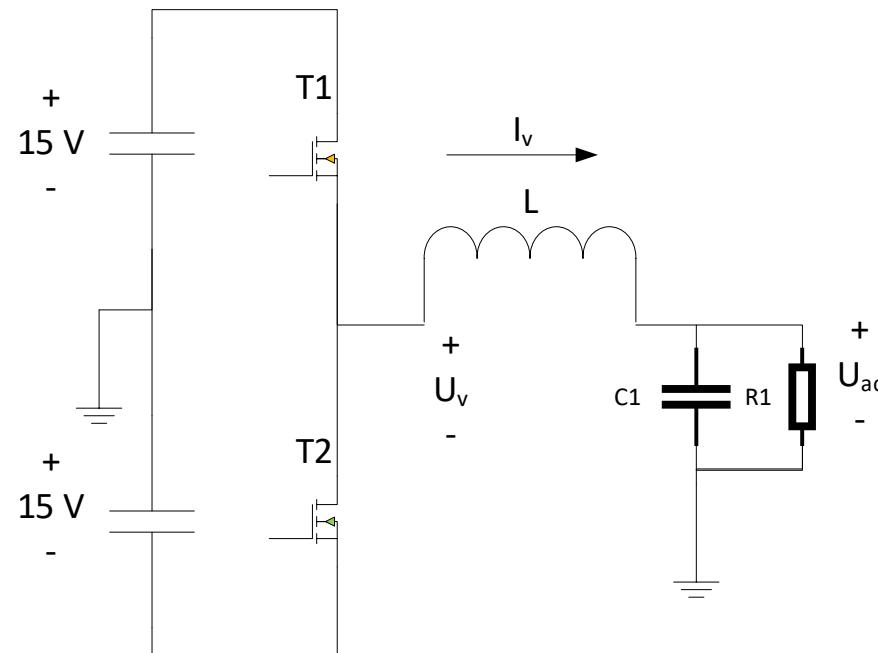
- $P_s = \frac{1}{2} V_d I_{sw,aw} f_s (t_{c(on)} + t_{c(off)})$
- $I_{sw,av} = I_{L,av}$

- Further reading see document "Losses" in Lisam/Tutorials



# Half-bridge converter example

- Total dc-voltage, positive-to-negative side
  - $U_d = 30V$
- DC-voltage positive and negative side to ground
  - $\frac{U_d}{2} = \pm 15V$



# DC/AC converter losses

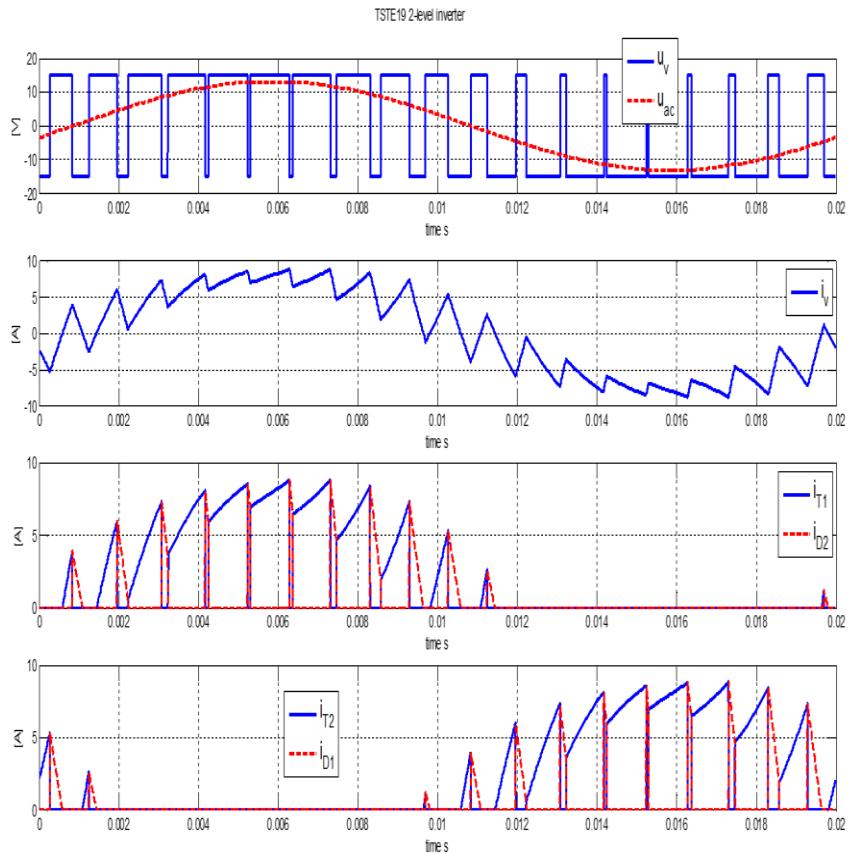
*Conduction losses (Both switches)*

- $P_{on} = 2 \cdot r_{ds(on)} I_{sw,rms}^2 =$   
 $= 2D \cdot r_{ds(on)} I_{L,av}^2 =$   
 $= \{D_{av} = 0.5\} = r_{ds(on)} I_{L,av}^2$

*Switching losses (total average for both switches in a half-bridge)*

- $P_s = \frac{1}{2} V_d I_{sw,av} f_s (t_{c(on)} + t_{c(off)})$
- $I_{sw,av} = \frac{2\sqrt{2}}{\pi} I_{v,rms} = 0.9 I_{v,rms}$   
 (based on full-wave pulses)

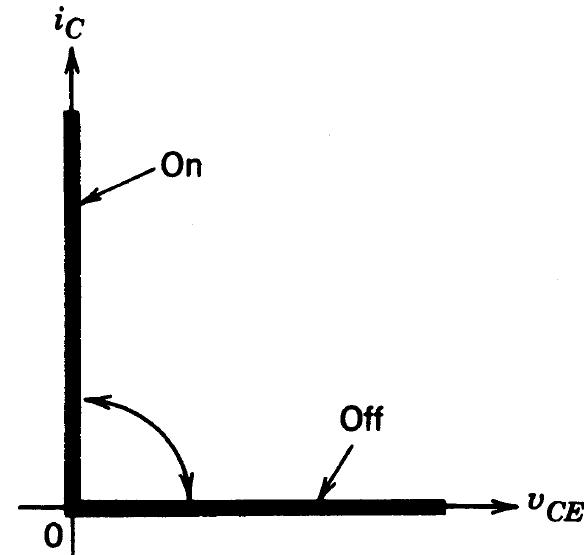
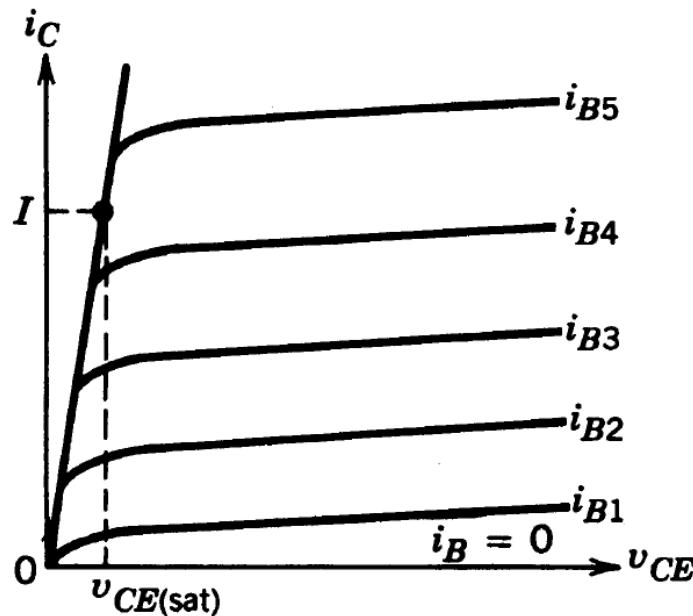
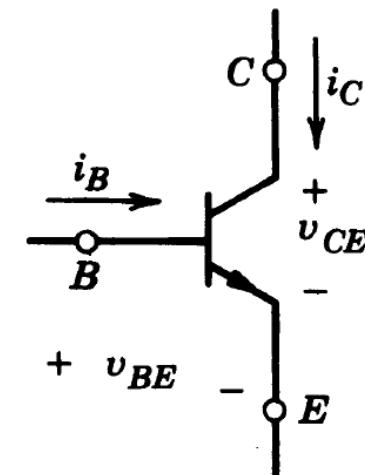
- Further reading see document “Losses” in Lisam/Tutorials



VSC Toolbox version 3.52, 23-Nov-2015 19:47:38

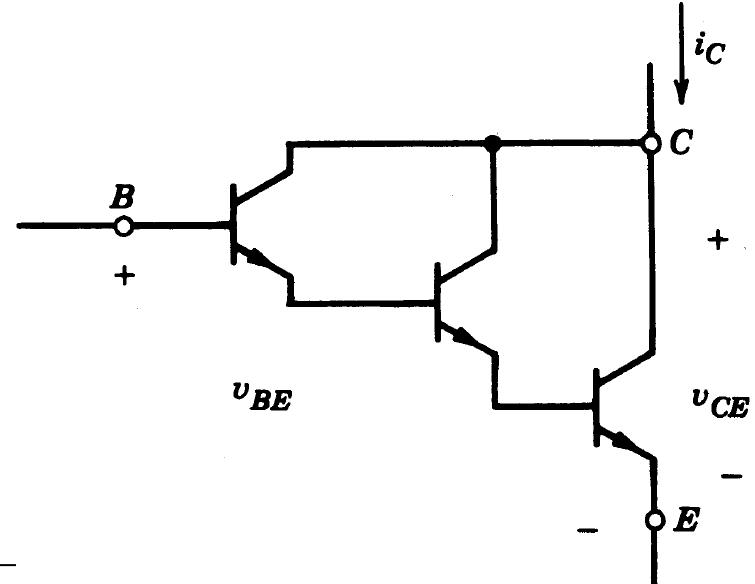
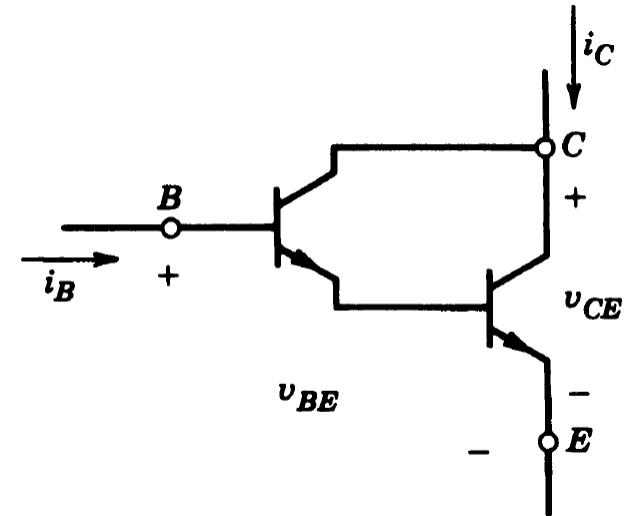
# Bipolar junction transistors (BJT)

- Current controlled by base current  $i_B$
- $5 < h_{FE} = \frac{I_C}{I_B} < 10$  for power BJT
- Possible to turn on and off



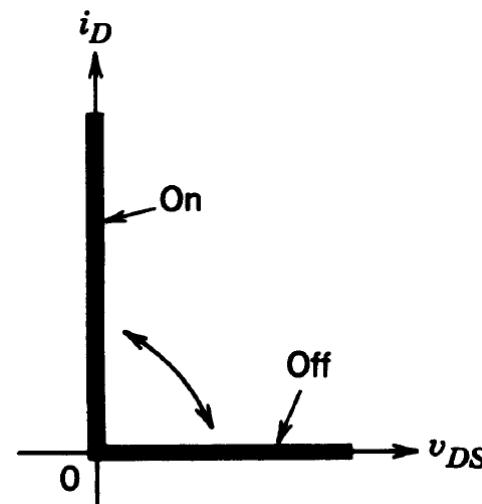
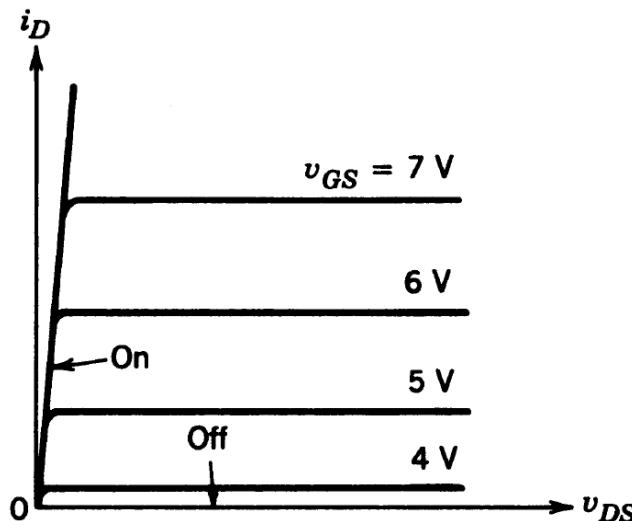
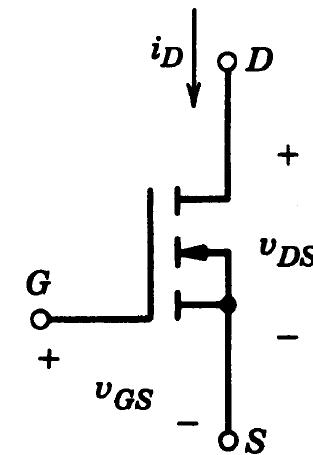
# Darlington bipolar transistors

- Increase  $h_{FE}$
- Increases also  $v_{CEsat}$ . Higher losses!
- $0.1 \text{ us} < \text{switching time} < 10 \text{ us}$
- Integrated on a single silicon chip

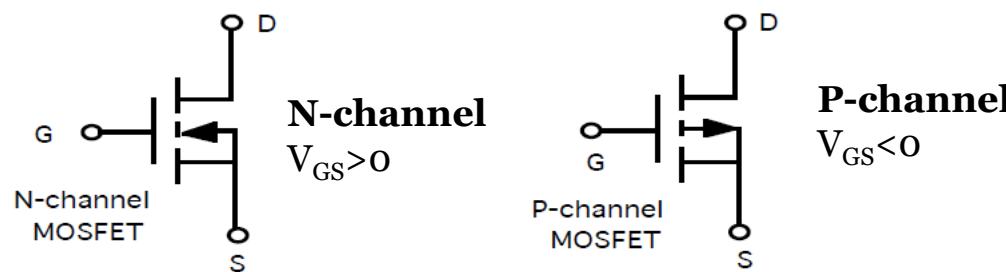
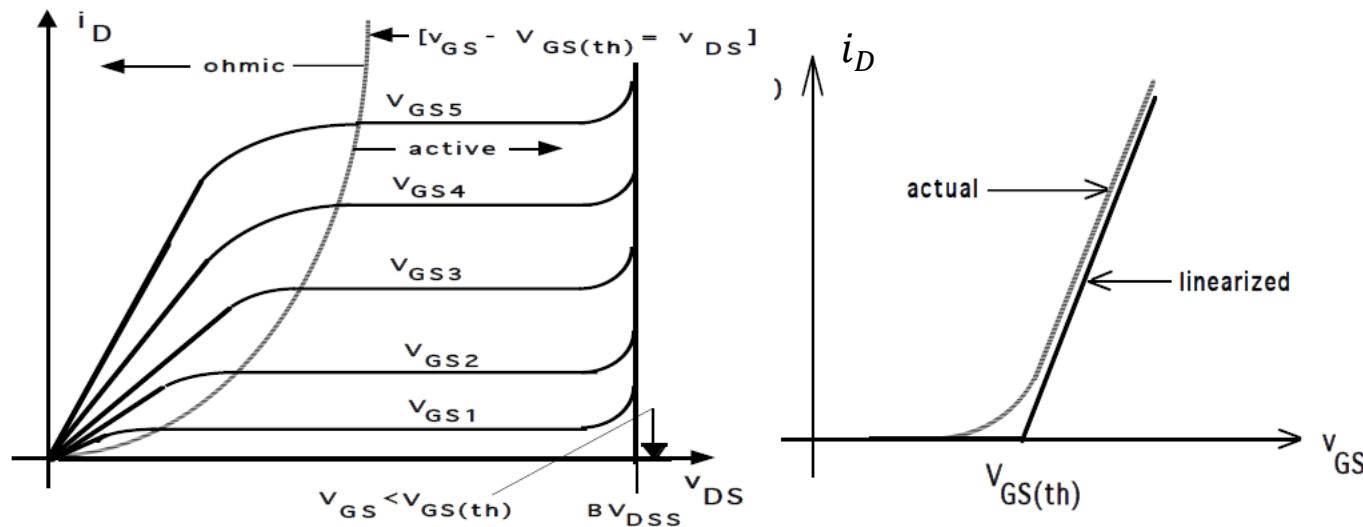


# MOSFET transistors

- Voltage controlled,  $V_{GS} > V_{GS(\text{th})}$
- Fast switching
  - $10 \text{ ns} < t < 500 \text{ ns}$
- Tradeoff  $R_{\text{on}}$  vs Blocking voltage
- Bidirectional current conduction
- Built in “body” diode



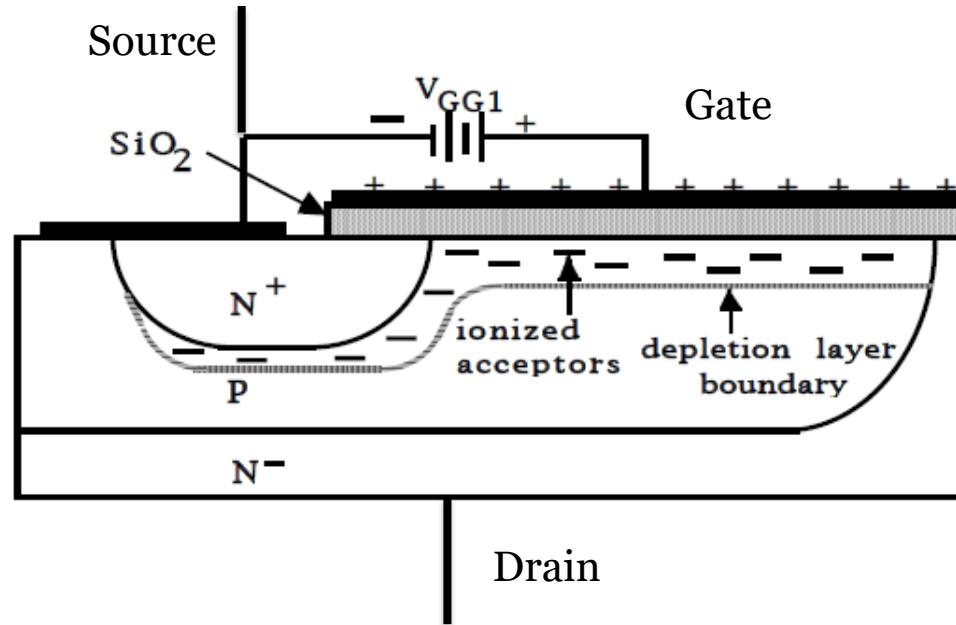
## MOSFET I-V Characteristics and Circuit Symbols



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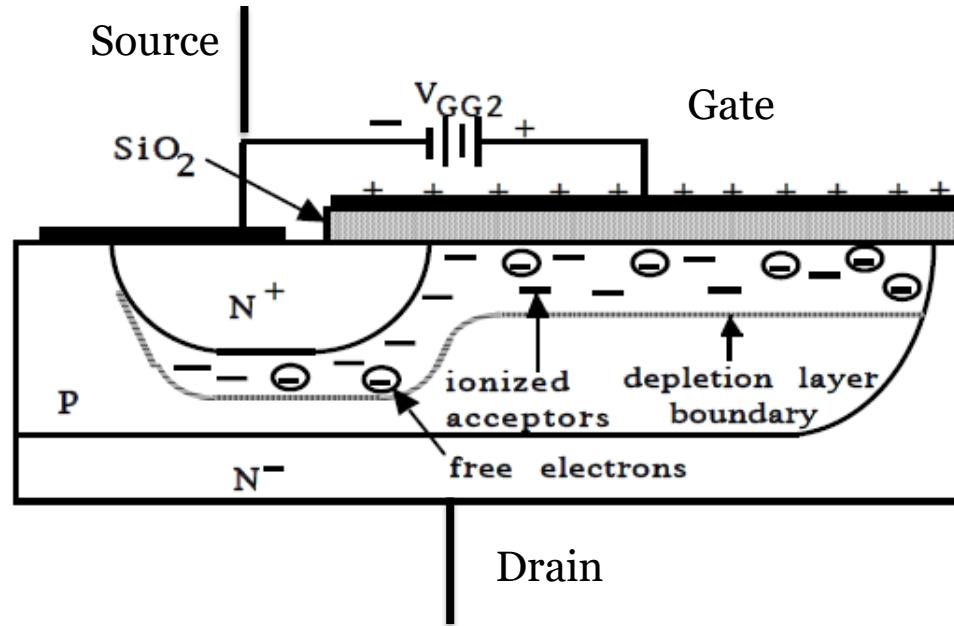
# MOSFET channel conduction control

- Low gate voltage
  - $V_{GS} \ll V_{GS(\text{th})}$
- Inversion layer isolating drain N<sup>-</sup> from source N<sup>+</sup>



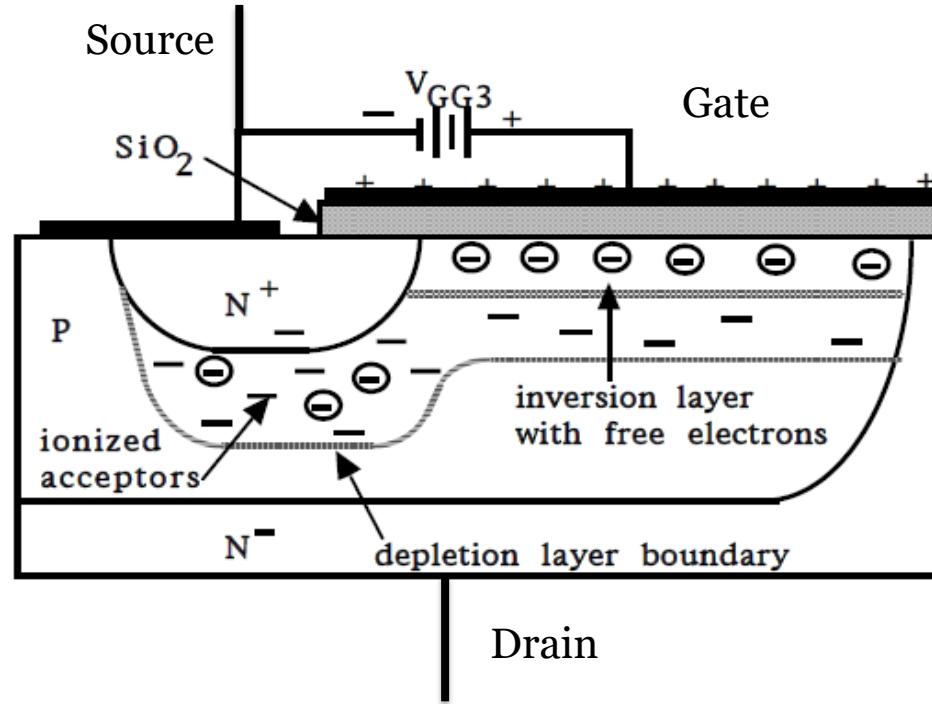
# MOSFET channel conduction control

- Increasing gate voltage but below threshold
  - $V_{GS} < V_{GS(\text{th})}$
- Inversion layer with some free electrons still isolating drain N<sup>-</sup> from source N<sup>+</sup>



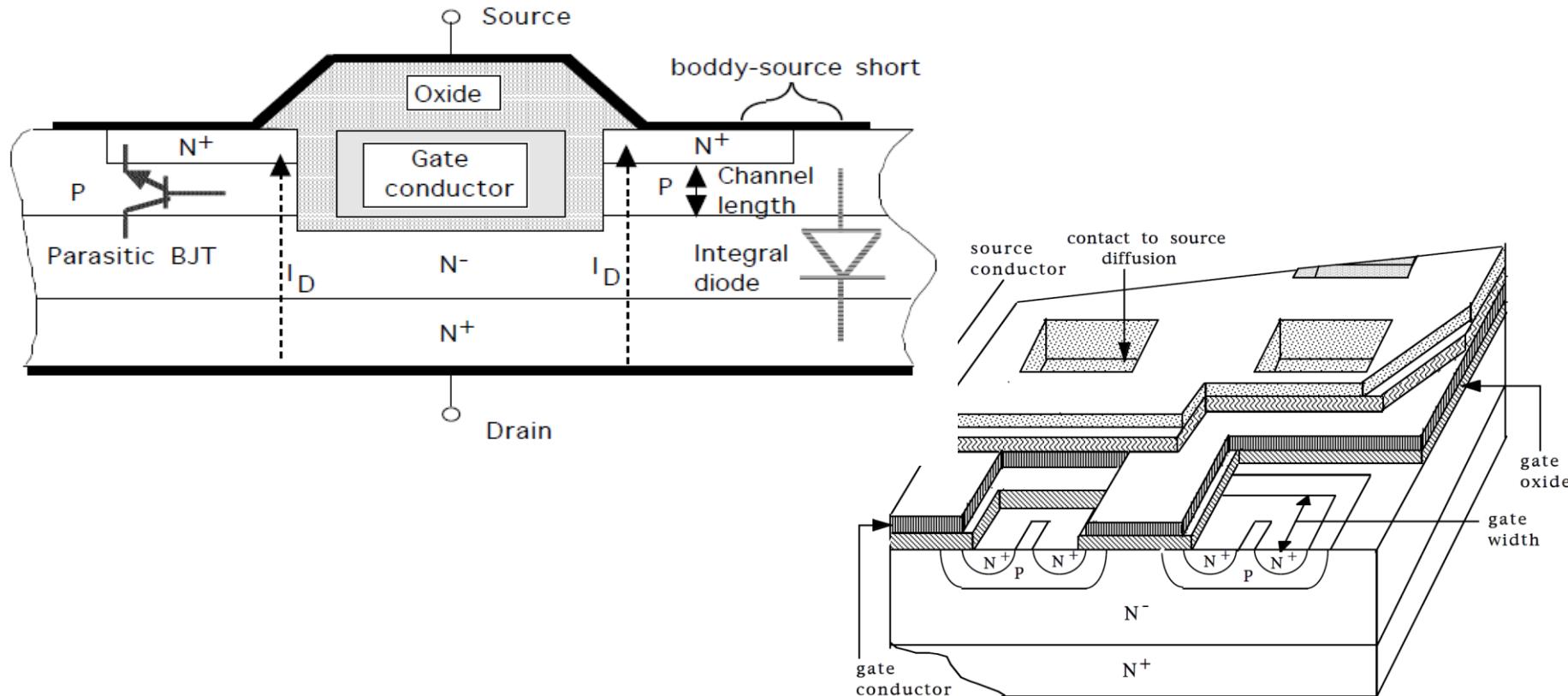
# MOSFET channel conduction control

- High gate voltage above threshold
- $V_{GS} > V_{GS(\text{th})}$
- Conductive channel of free electrons formed between drain N<sup>-</sup> and source N<sup>+</sup>



# MOSFET implementation

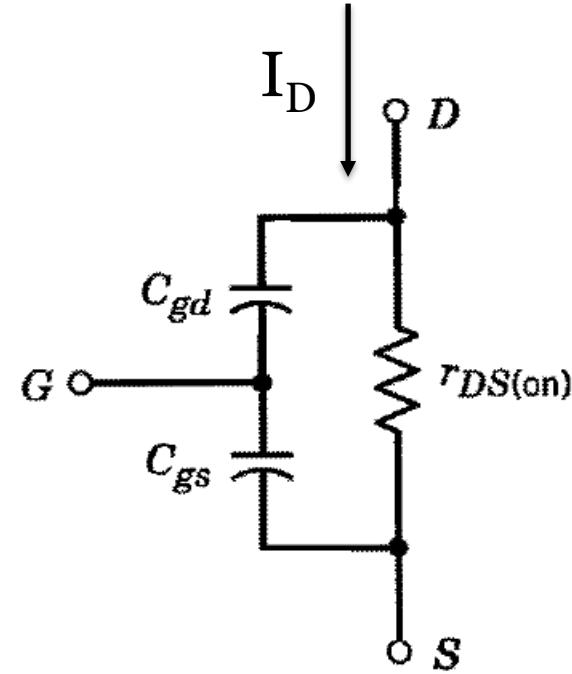
- Thousands of cells in parallel



# MOSFET on-state equivalent

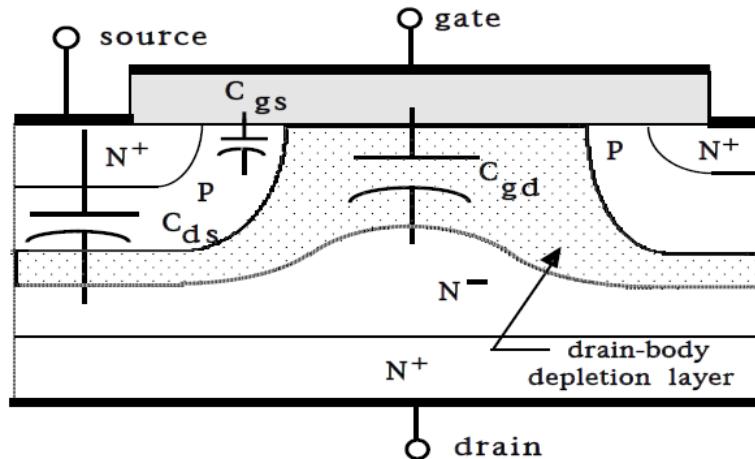
- On-state conduction losses

$$P_{on} = r_{DS(on)} I_D^2$$

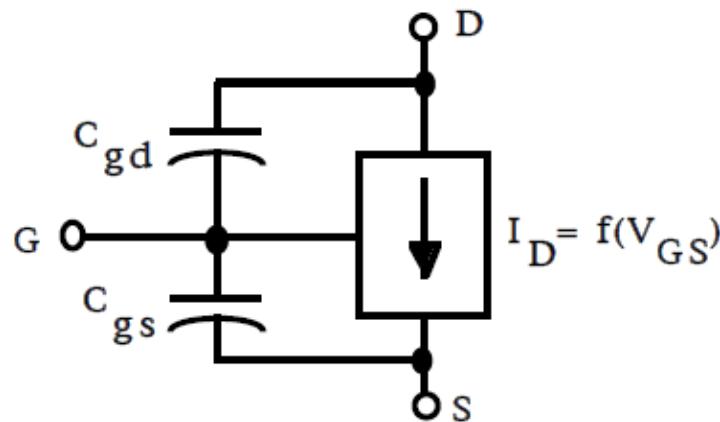
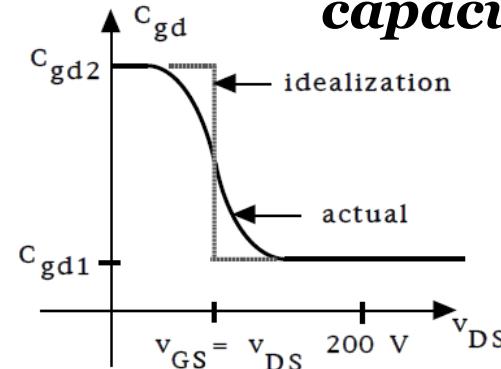


MOSFET equivalent circuit  
for on-state operation

# MOSFET turn-on/turn-off equivalent



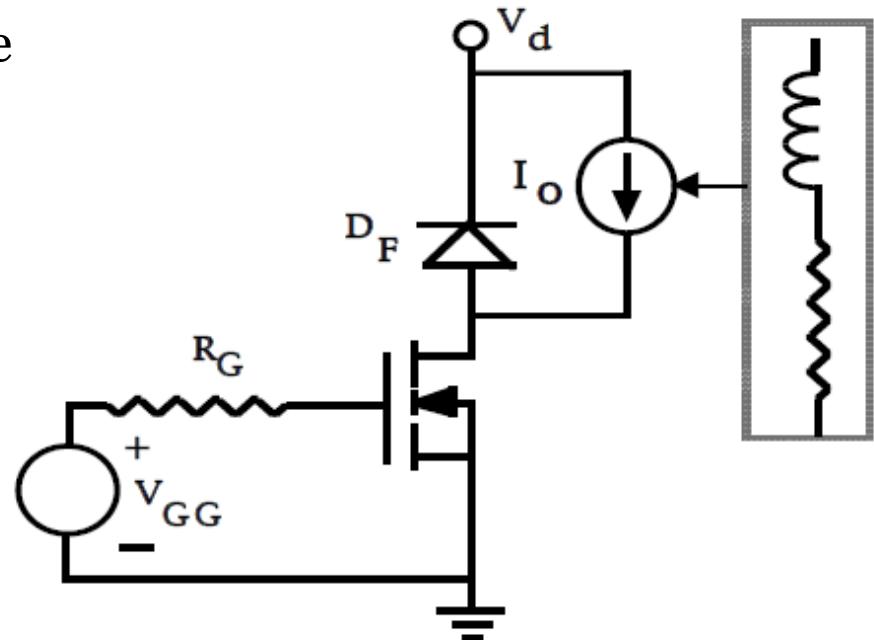
$C_{gd}$ : “Miller capacitance”



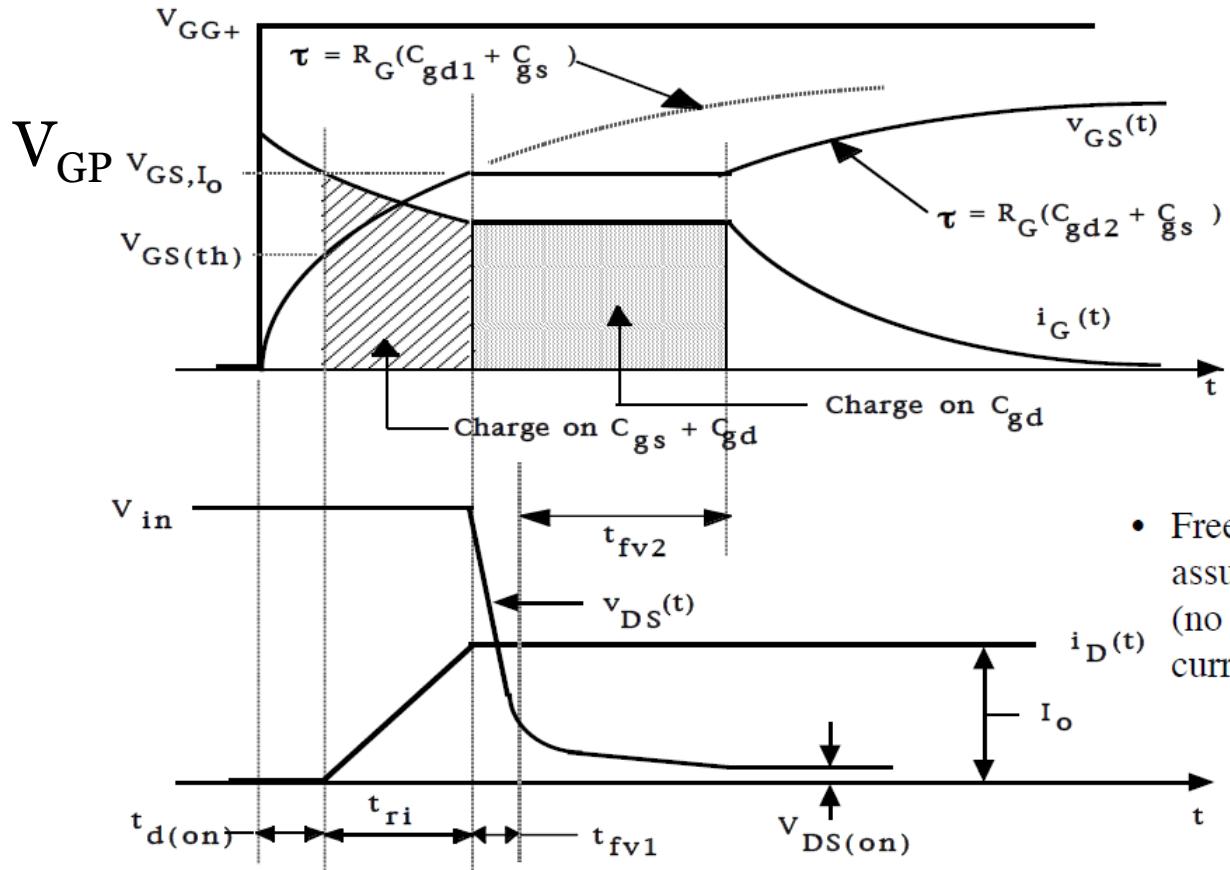
MOSFET equivalent circuit for off-state and active region operation

# Switching MOSFET – Diode pair

- The current  $I_o$  is either conducted through the diode (when MOSFET is off) or through the MOSFET
- Turn-on:  $V_{GG} \gg V_{GS(\text{th})}$
- Turn-off:  $V_{GG} = 0$



## MOSFET-based Buck Converter Turn-on Waveforms

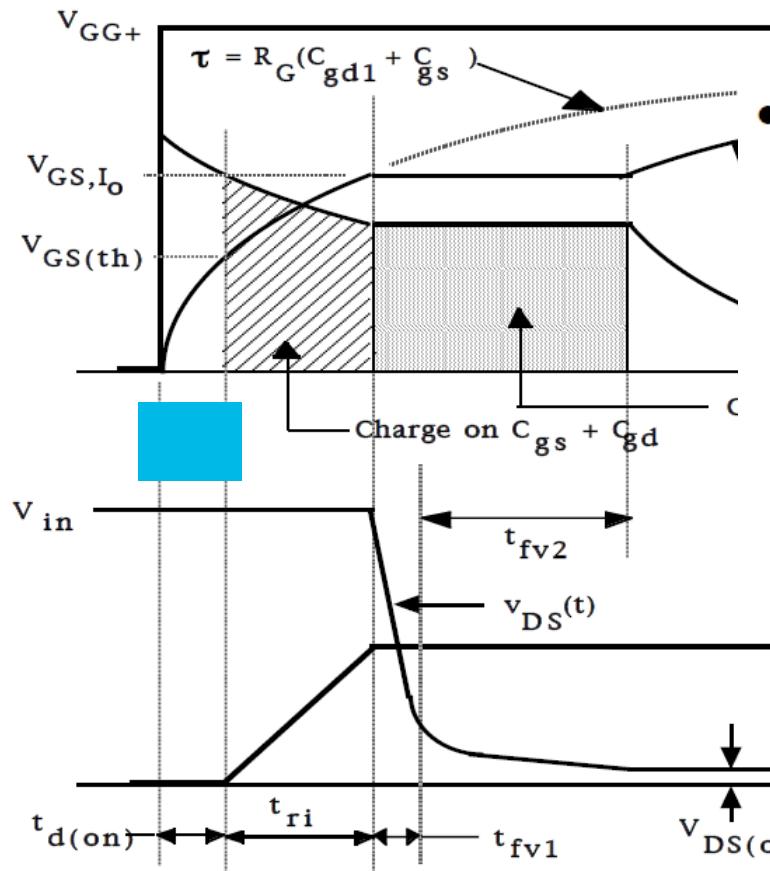


**“Miller plateau”**

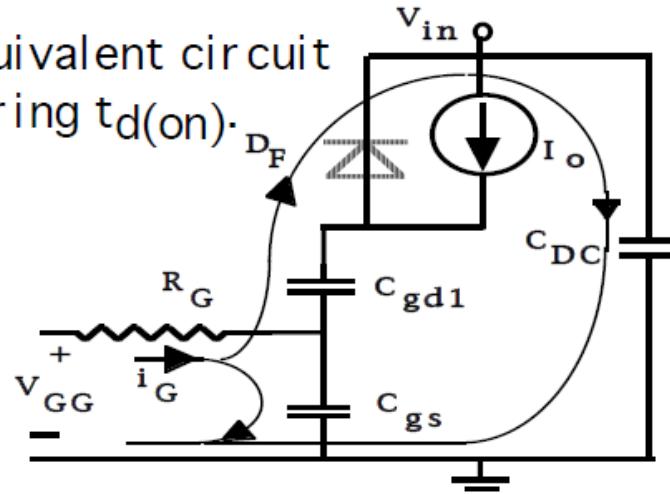
- Free-wheeling diode assumed to be ideal. (no reverse recovery current).

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## MOSFET-based Buck Converter Turn-on Waveforms



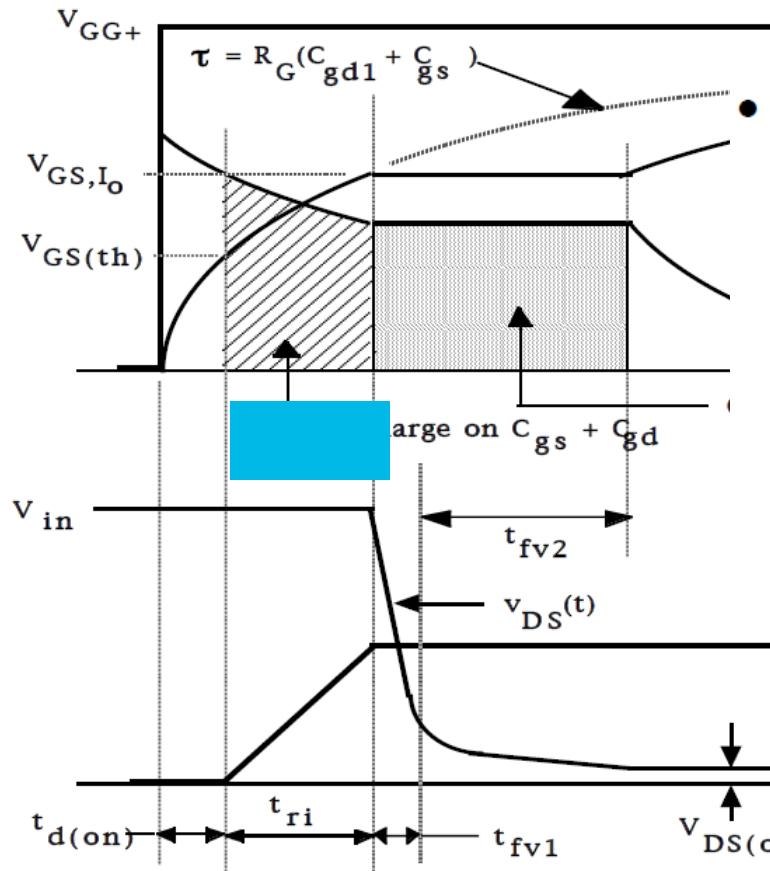
- Equivalent circuit during  $t_d(on)$ :



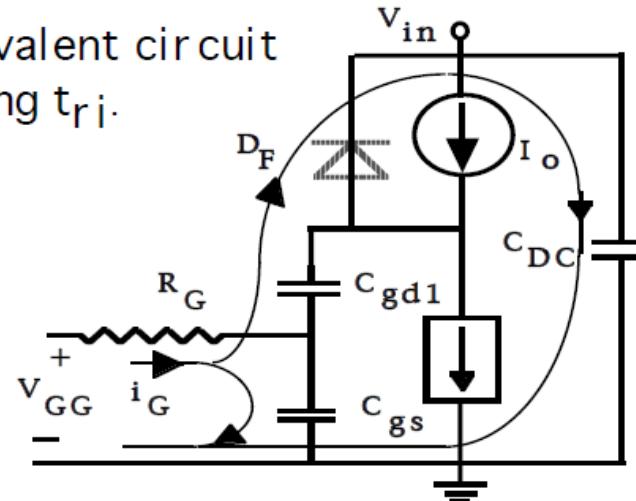
- $V_{gs} = V_{GG}(1 - e^{\frac{-t}{RC}})$
- $R = R_g$
- $C = C_{gs} + C_{gd}$

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## MOSFET-based Buck Converter Turn-on Waveforms



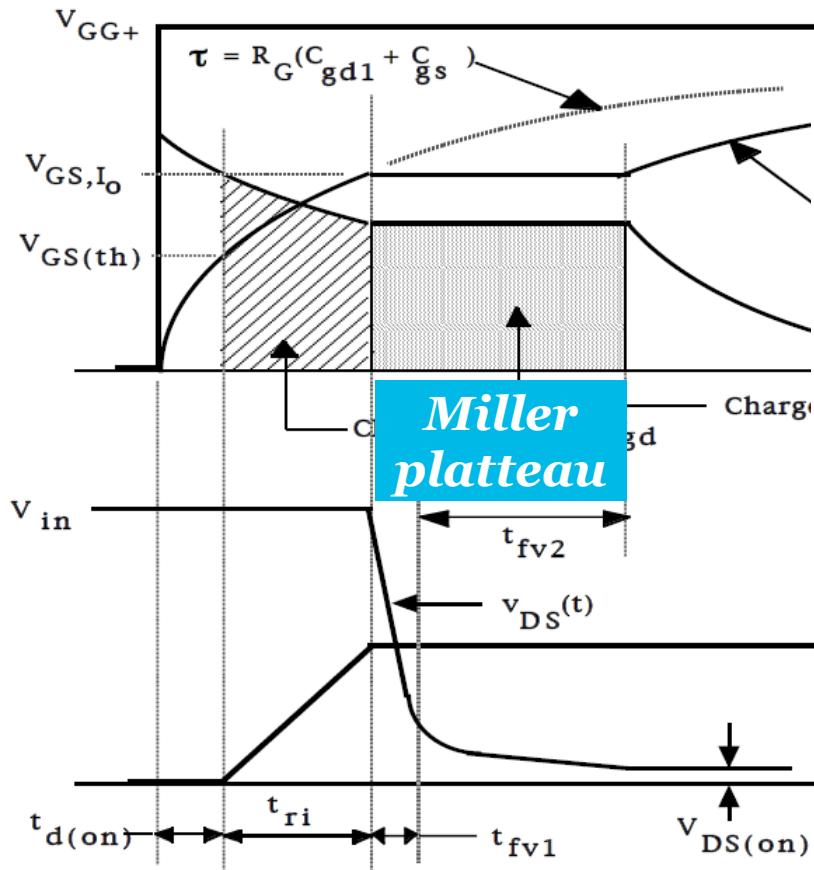
- Equivalent circuit during  $t_{ri}$ .



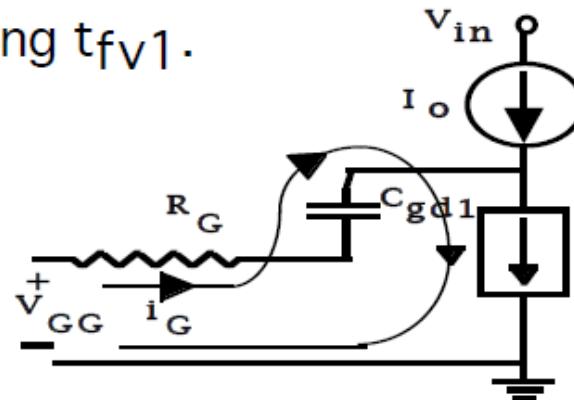
- $V_{gs} = V_{GG} \left( 1 - e^{\frac{-t}{RC}} \right)$
- $R = R_g$
- $C = C_{gs} + C_{gd}$

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## MOSFET-based Buck Converter Turn-on Waveforms



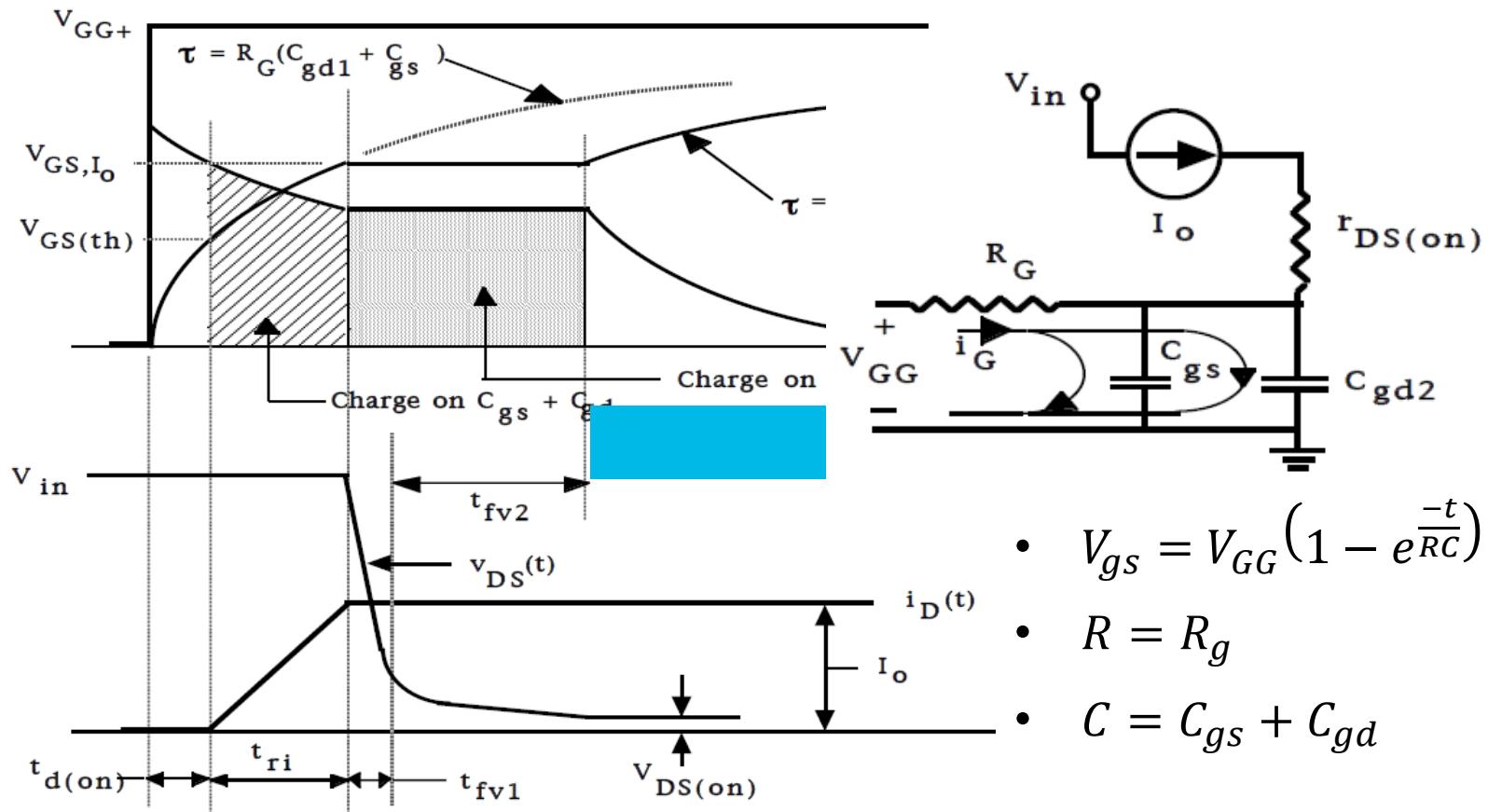
- Equivalent circuit during  $t_{fv1}$ .



- $V_{gs} = V_{GP}$
- $i_g = \frac{V_{GG}-V_{GP}}{R_g} = C_{gd} \frac{dV_{ds}}{dt}$

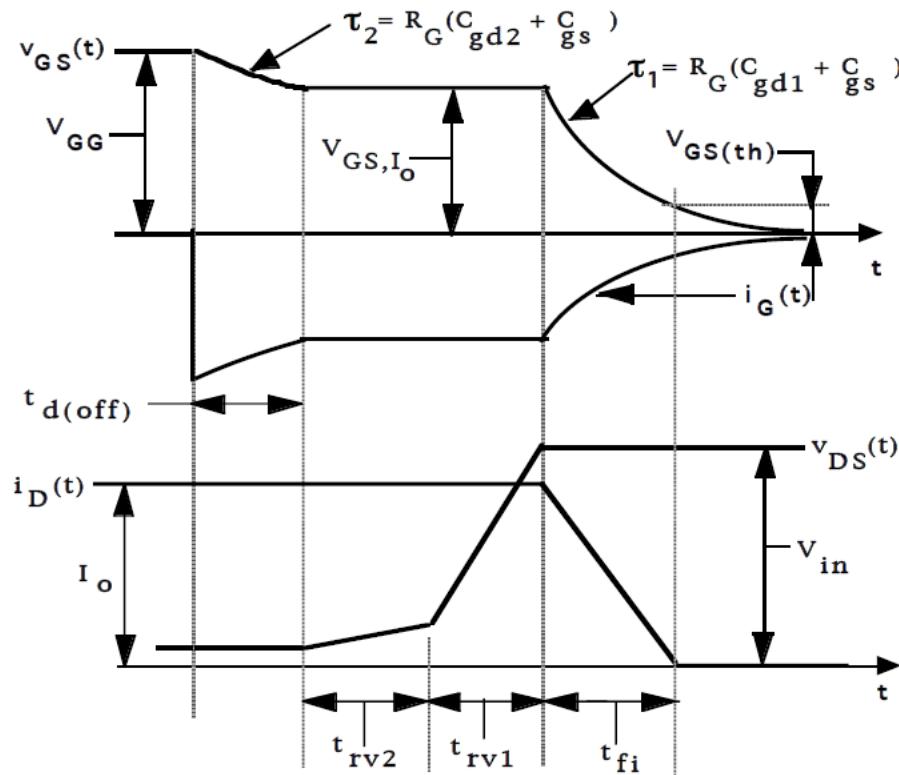
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## MOSFET-based Buck Converter Turn-on Waveforms



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## MOSFET-based Buck Converter Turn-off Waveforms



- Assume ideal free-wheeling diode.
- Essentially the inverse of the turn-on process.
- Model quantitatively using the same equivalent circuits as for turn-on. Simply use correct driving voltages and initial conditions

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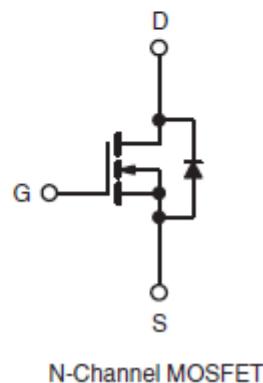
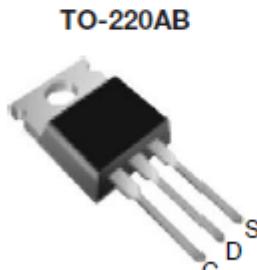
# MOSFET data sheet

**IRF540, SiHF540**

Vishay Siliconix

## Power MOSFET

PRODUCT SUMMARY		
$V_{DS}$ (V)	100	
$R_{DS(on)}$ ( $\Omega$ )	$V_{GS} = 10$ V	0.077
$Q_g$ (Max.) (nC)	72	
$Q_{gs}$ (nC)	11	
$Q_{gd}$ (nC)	32	
Configuration	Single	

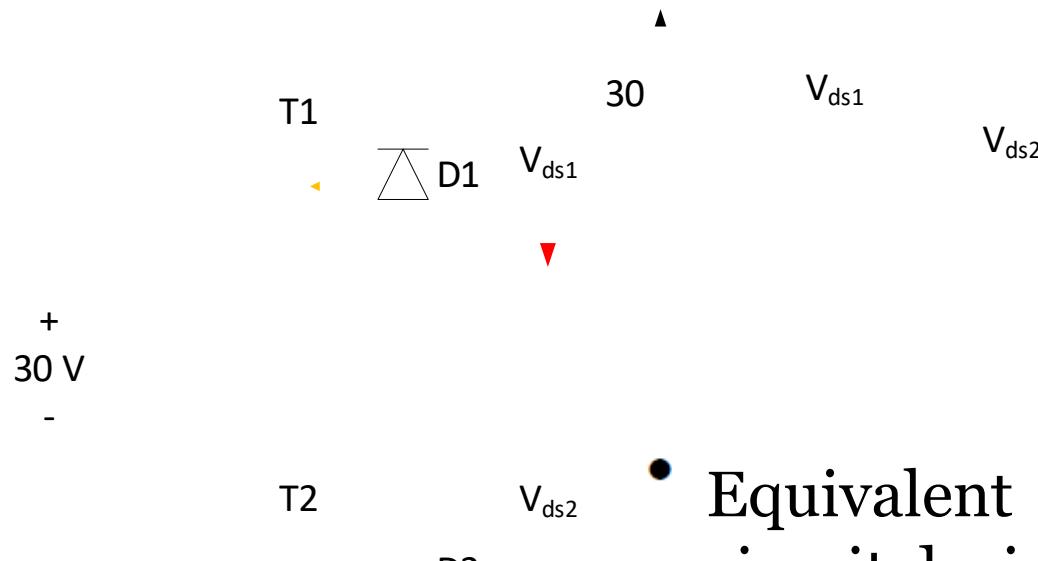


N-Channel MOSFET

## Definitions of device capacitances.

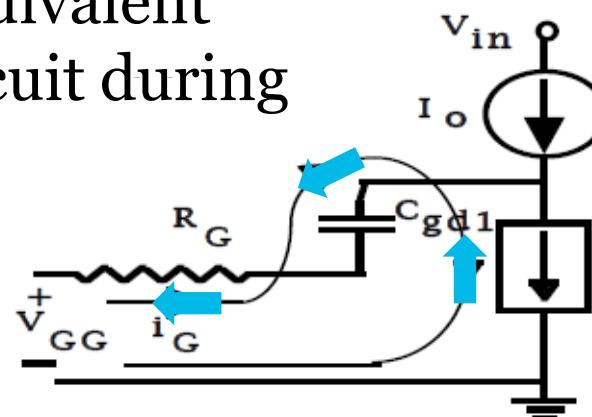
- $C_{iss} = C_{GS} + C_{GD}$ ,  $C_{DS}$  shorted
- $C_{rss} = C_{GD}$
- $C_{oss} = C_{DS} + C_{GD}$

# MOSFET T1 turn-on. Disturbance on T2 ??



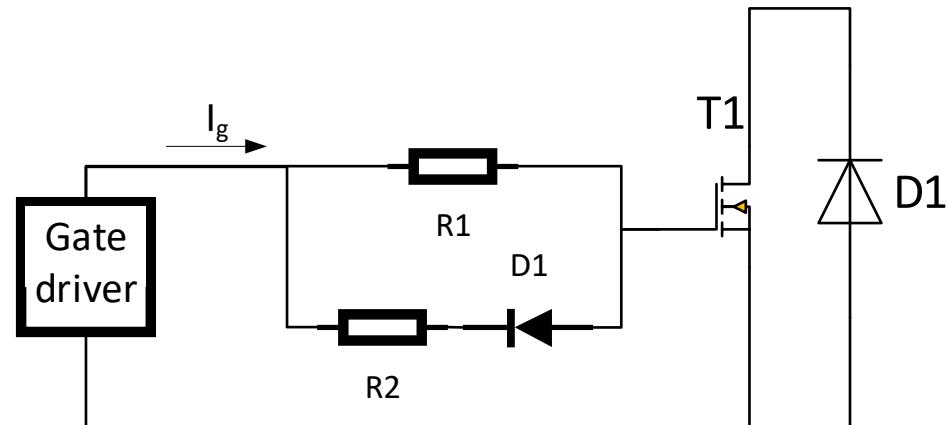
- $V_{GG2} = 0$
- $i_{g2} = C_{gd} \frac{dV_{ds}}{dt}$
- $V_{gs2} = V_{GG2} + R_g i_{g2}$
- $V_{gs2} > V_{gs(th)}$
- **T2 TURN-ON**

- Equivalent circuit during  $t_{rv1}$

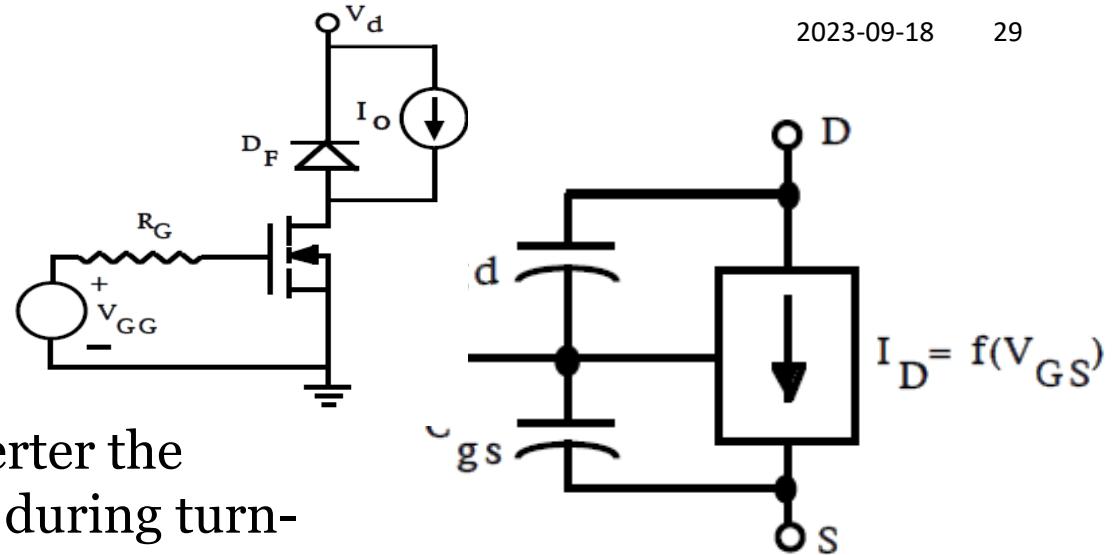


# Gate resistance control

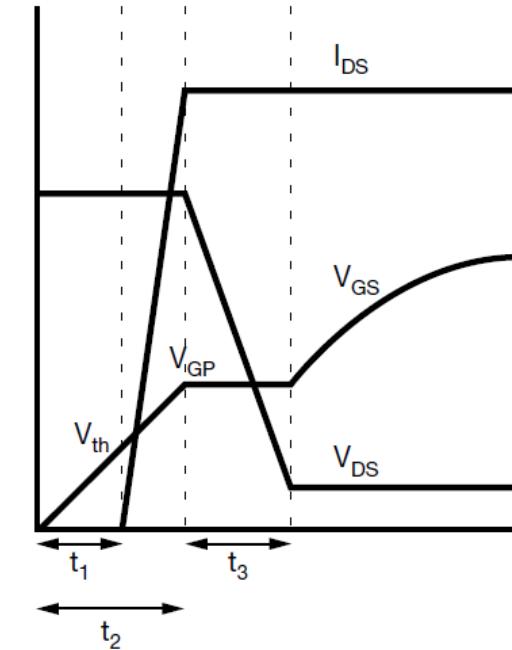
- Separate  $R_{g(on)}=R_1$  and  $R_{g(off)}=R_2$
- Diode D1 makes R1 active during turn-on and R2 active during turn-off  
 **$R_2 \ll R_1$**
- Reduced  $R_{g(off)}$  to prevent parasitic turn-on at high  $dv/dt$



## 5-100

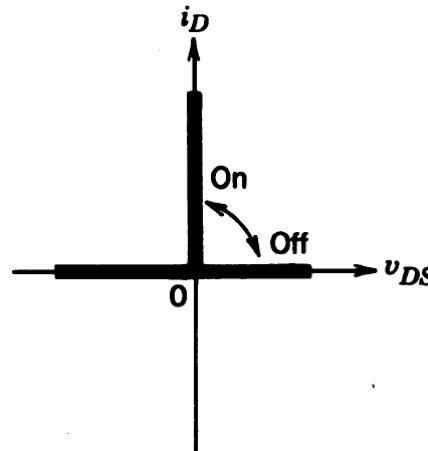
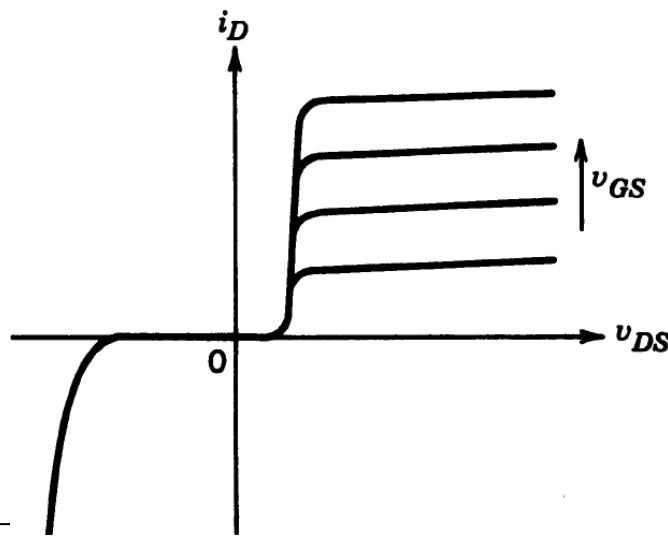
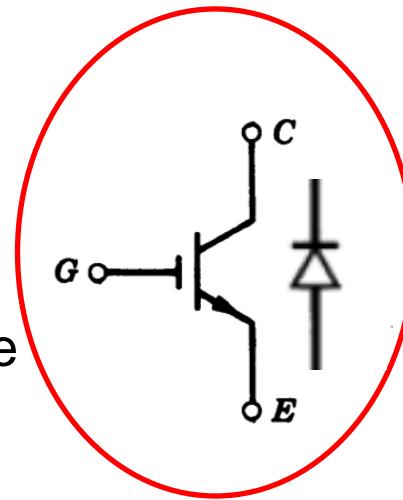


- For a step-down converter the  $dV_{DS}/dt$  of a MOSFET during turn-on is defined by  $V_d$  (assume  $V_{dson}=0$ ) and  $t_{fv}$ .
- $V_{ds} = 100 \text{ V}$ ,  $t_{fv} = t_3 = 200 \text{ ns}$
- The gate-drain capacitance,  $C_{gd} = 120 \text{ pF}$ . The miller plateau voltage  $V_{GP} = 4 \text{ V}$
- Calculate the gate resistance,  $R_G$  for a gate drive with  $V_{GG} = 10 \text{ V}$  which gives a  $dV_{DS}/dt$  as specified.



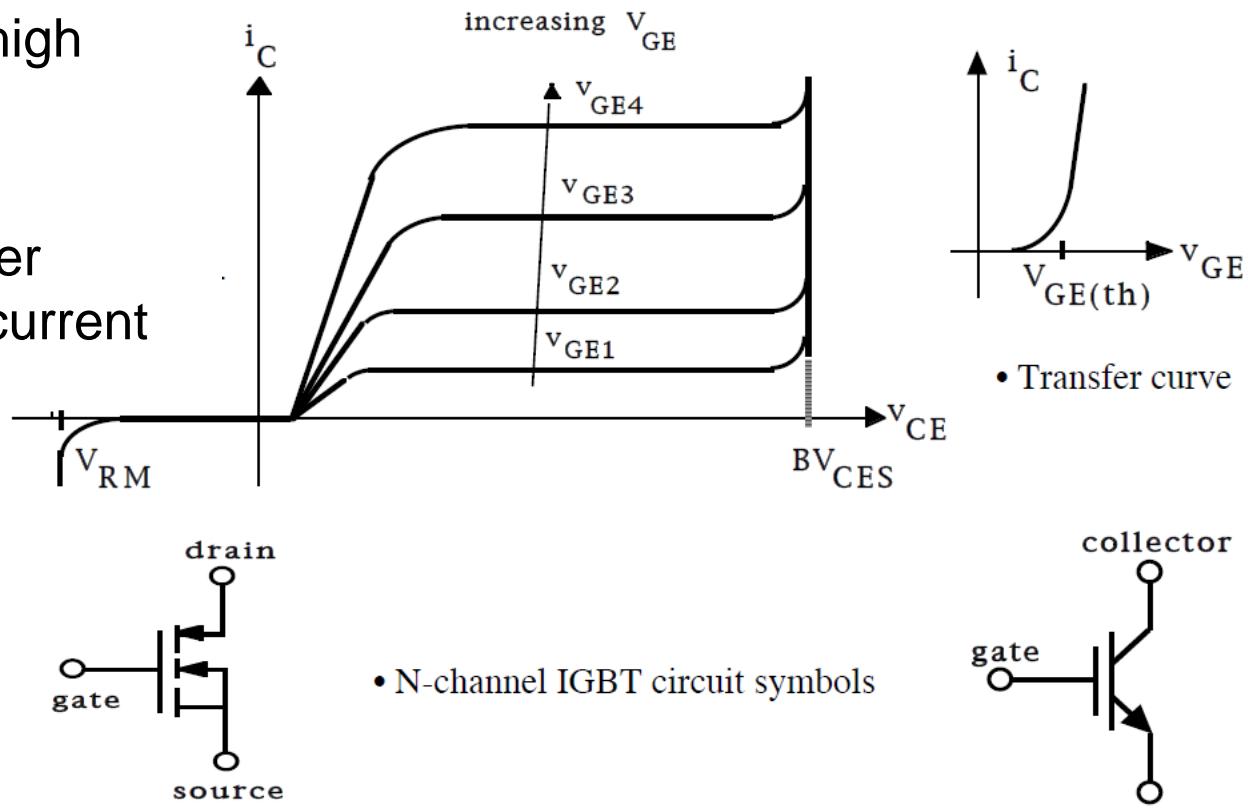
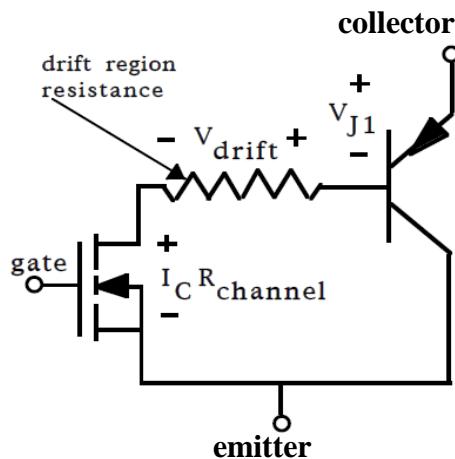
# Insulated gate bipolar (IGBT)

- High input impedance
- Small on-state voltage
- Large blocking voltage
- Combined with anti-parallel diode



# Insulated gate bipolar (IGBT) implementation

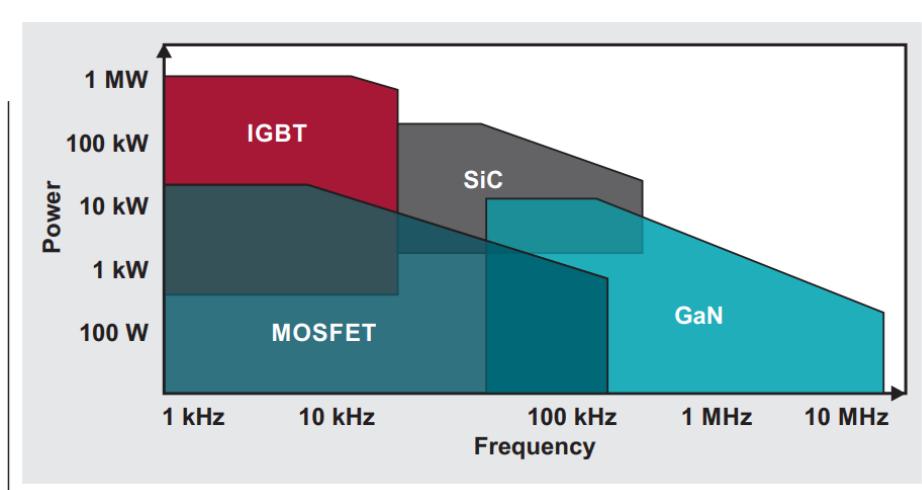
- Bipolar carrier conduction (electron & holes)  
low voltage drop at high current
- PN-junction in PNP transistor gives higher voltage drop at low current



# Semiconductor materials

- **Silicon**  
MOSFET & IGBT
- **Silicon Carbide**  
MOSFET
- **Gallium Nitride**  
MOSFET, HEMT

Parameter	GaN	SiC	Si
Electron mobility ( $\text{cm}^2 / \text{V*s}$ )	1800	900	1400
Energy gap (eV)	3.5	3.26	1.12
Breakdown electric field (MV/cm)	3.3	3	0.3
Thermal conductivity (W/cm*K)	1.3	4.9	1.5
Saturation drift velocity (Mcm/s)	27	27	10



Source: Wide-bandgap semiconductors:  
Performance and benefits of GaN versus SiC,  
Analog Design Journal, Texas Instruments 2020

# Lecture 4

Thermal management

# Cooling requirement motivation

- Component failure rate increase with temperature increase
- Capacitors
  - Electrolyte evaporation rate increase with temperature
- Magnetic components
  - Losses in magnetic components increase when  $T > 100$  degrees
  - Winding insulation degrades when  $T > 100$  degrees
- Semiconductors
  - Breakdown voltage decrease
  - Leakage current and switching time increases
  - Power sharing problems when parallel or serial devices

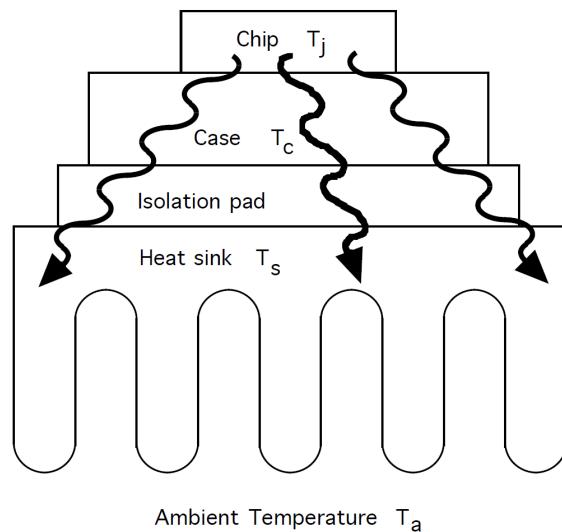
# Heat sinks

- Different shapes and material
- Based on convection and radiation
  - Natural convection
  - Forced-air convection
- Examples: Computers, trains, ....



# Thermal model with electric analogy

- Power corresponds to current,
- Temperature corresponds to voltage,
- Thermal resistance  $R_\Theta$  (or  $R_{th}$ ) corresponds to ohmic resistance



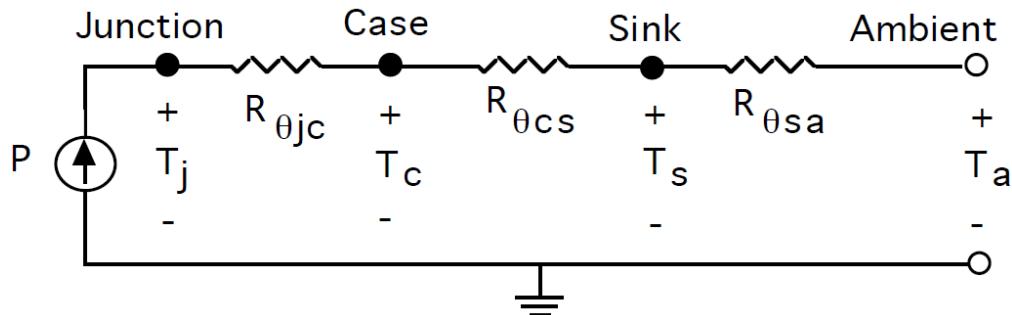
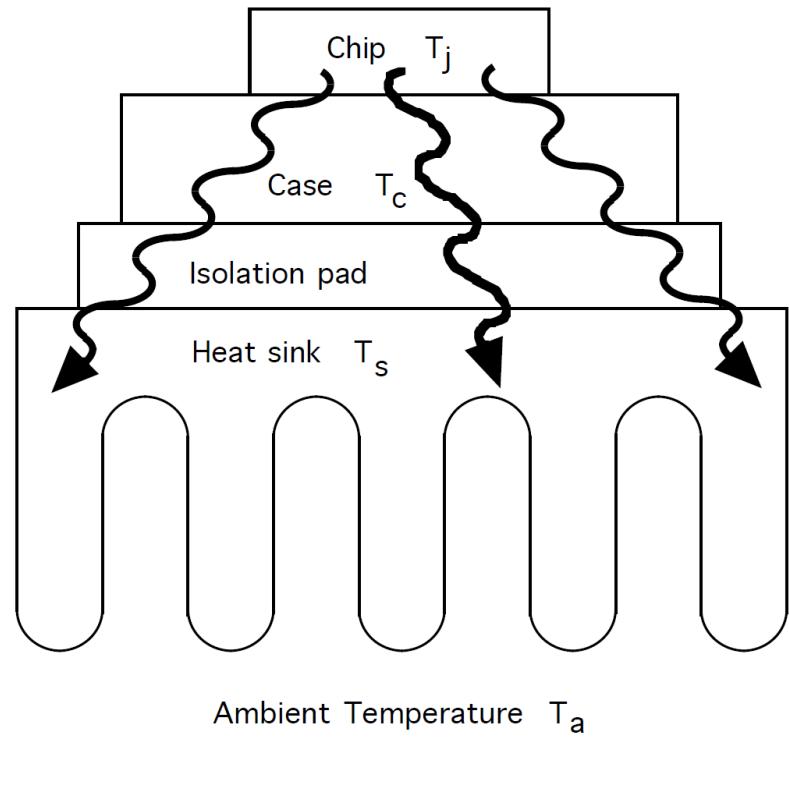
$$\Delta T = P \cdot R_\Theta [\text{K/W}]$$

$$R_\Theta = \frac{\Delta T}{P} [\text{K/W}]$$

# Multiple layer structure model

- Typical cooling setup
  - Different sizes and materials
- Electric model of the power transfer from power source to the environment

$$T_j = T_c + \Delta T_{jc} = T_c + P \cdot R_{\Theta,jc}$$

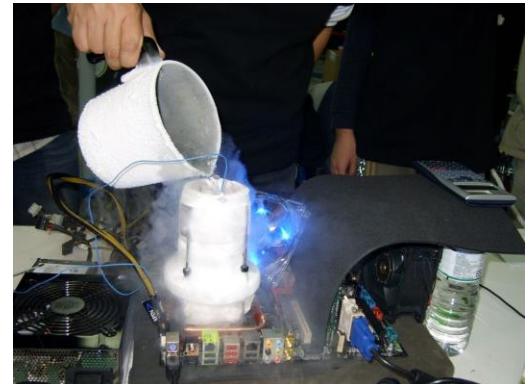


## 29-6

- A MOSFET used in a step-down converter has an on-state loss of 50 W and a switching loss given by  $10^{-3} f_s$  (in watts) where  $f_s$  is the switching frequency in hertz.
- The junction-to-case thermal resistance  $R_{th,jc}$  is 1 K/W and the maximum junction temperature  $T_{j,max}$  is 150°C.
- Assuming the case temperature is 50°C, estimate the maximum allowable switching frequency.

# Other cooling approaches

- Liquid cooling
  - Allow larger heatsinks,  
placed away from power source
- Thermal towers, heatpipes
  - Similar principle as in a refrigerator (phase shifting)
  - Connect a larger heatsink without large thermal resistance
- Liquid nitrogen
  - Force temperature down below  $T_a$
  - Expensive
  - Water condensation problems
  - Material stress problems



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